

<b>Notice of References Cited</b>	Application/Control No. 10/689,672	Applicant(s)/Patent Under Reexamination HAN ET AL.	
	Examiner Yewebdar T. Tadesse	Art Unit 1734	Page 1 of 1

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*	B	US-5,059,266	10-1991	Yamane et al.	156/64
	C	US-			
	D	US-			
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	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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